Application/Control No. Applicant(s)/Patent Under Reexamination 10/552,029 CHANG ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Qiuwen Mi 1655 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY * 07-2003 424/773 US-2003/0134003 Fong et al. Α В US-US-С US-D US-Ε F US-US-G US-Н US-1 US-US-Κ US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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